

# FQA9N90C\_F109

## N-Channel QFET® MOSFET

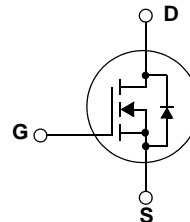
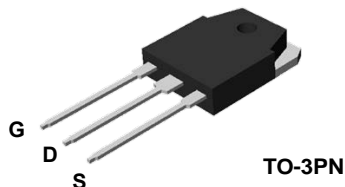
### 900 V, 9 A, 1.4 Ω

#### Features

- 9 A, 900 V,  $R_{DS(on)} = 1.4 \Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 4.5 \text{ A}$
- Low Gate Charge (Typ. 45 nC)
- Low Crss . 14 pF)
- 100% Avalanche Tested
- RoHS compliant

#### Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.



#### Absolute Maximum Ratings

Symbol	Parameter	FQA9N90C_F109	Unit
$V_{DSS}$	Drain-Source Voltage	900	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	9.0	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )	5.7	A
$I_{DM}$	Drain Current - Pulsed (Note 1)	36	A
$V_{GSS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	900	mJ
$I_{AR}$	Avalanche Current (Note 1)	9.0	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	28	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.0	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	280	W
	- Derate above $25^\circ\text{C}$	2.22	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

#### Thermal Characteristics

Symbol	Parameter	FQA9N90C_F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.45	$^\circ\text{C}/\text{W}$
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	$^\circ\text{C}/\text{W}$

**Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQA9N90C	FQA9N90C_F109	TO-3PN	--	--	30

**Electrical Characteristics**  $T_C = 25^\circ\text{C}$  unless otherwise noted

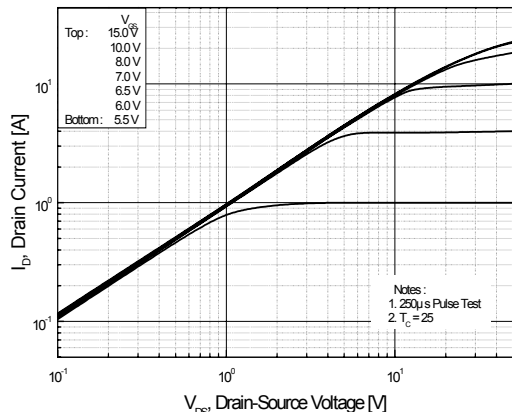
Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit	
<b>Off Characteristics</b>							
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	900	--	--	V	
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.99	--	$\text{V}/^\circ\text{C}$	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 900\text{ V}, V_{GS} = 0\text{ V}$	--	--	10	$\mu\text{A}$	
		$V_{DS} = 720\text{ V}, T_C = 125^\circ\text{C}$	--	--	100	$\mu\text{A}$	
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA	
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA	
<b>On Characteristics</b>							
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	3.0	--	5.0	V	
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 4.5\text{ A}$	--	1.12	1.4	$\Omega$	
$g_{FS}$	Forward Transconductance	$V_{DS} = 50\text{ V}, I_D = 4.5\text{ A}$ (Note 4)	--	9.2	--	S	
<b>Dynamic Characteristics</b>							
$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	2100	2730	pF	
$C_{oss}$	Output Capacitance		--	175	230	pF	
$C_{rSS}$	Reverse Transfer Capacitance		--	14	18	pF	
<b>Switching Characteristics</b>							
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 450\text{ V}, I_D = 11.0\text{ A},$ $R_G = 25\ \Omega$	--	50	110	ns	
$t_r$	Turn-On Rise Time		--	120	250	ns	
$t_{d(off)}$	Turn-Off Delay Time		(Note 4, 5)	--	100	210	ns
$t_f$	Turn-Off Fall Time		--	75	160	ns	
$Q_g$	Total Gate Charge	$V_{DS} = 720\text{ V}, I_D = 11.0\text{ A},$ $V_{GS} = 10\text{ V}$	--	45	58	nC	
$Q_{gs}$	Gate-Source Charge		(Note 4, 5)	--	13	--	nC
$Q_{gd}$	Gate-Drain Charge		--	18	--	nC	
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>							
$I_S$	Maximum Continuous Drain-Source Diode Forward Current		--	--	9.0	A	
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current		--	--	36	A	
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 9.0\text{ A}$	--	--	1.4	V	
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{ V}, I_S = 9.0\text{ A},$ $dI_F / dt = 100\text{ A}/\mu\text{s}$	--	550	--	ns	
$Q_{rr}$	Reverse Recovery Charge		(Note 4)	--	6.5	--	$\mu\text{C}$

**NOTES:**

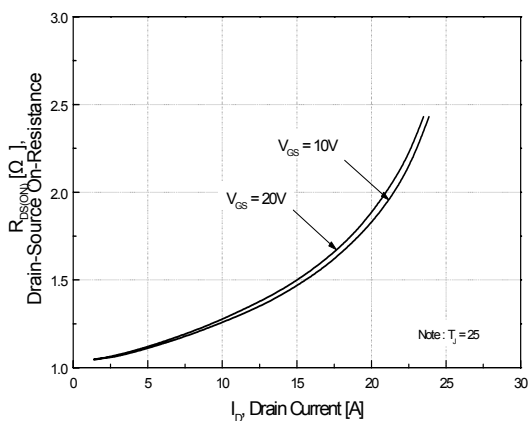
1. Repetitive Rating : Pulse width limited by maximum junction temperature
2.  $L = 21\text{ mH}, I_{AS} = 9.0\text{ A}, V_{DD} = 50\text{ V}, R_G = 25\ \Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 9.0\text{ A}, di/dt \leq 200\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width  $\leq 300\ \mu\text{s}$ , Duty cycle  $\leq 2\%$
5. Essentially independent of operating temperature

## Typical Performance Characteristics

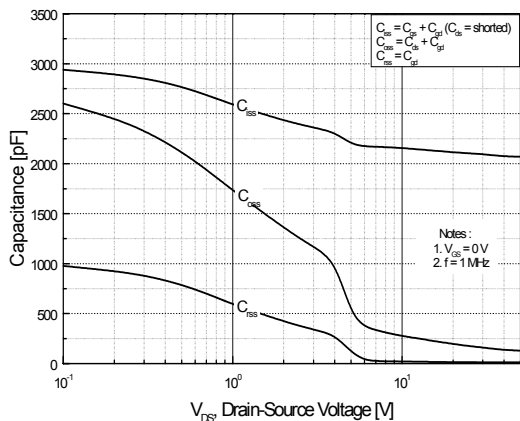
**Figure 1. On-Region Characteristics**



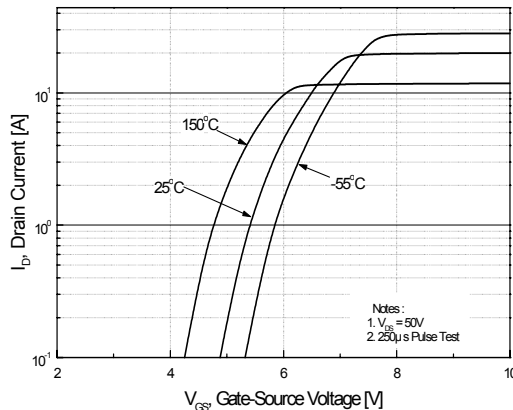
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



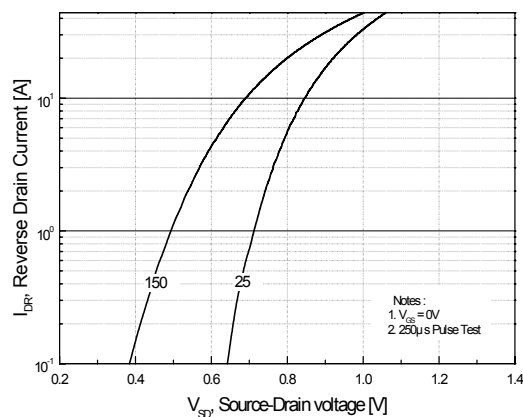
**Figure 5. Capacitance Characteristics**



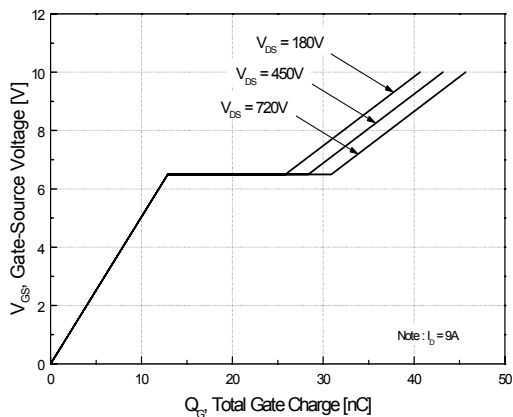
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

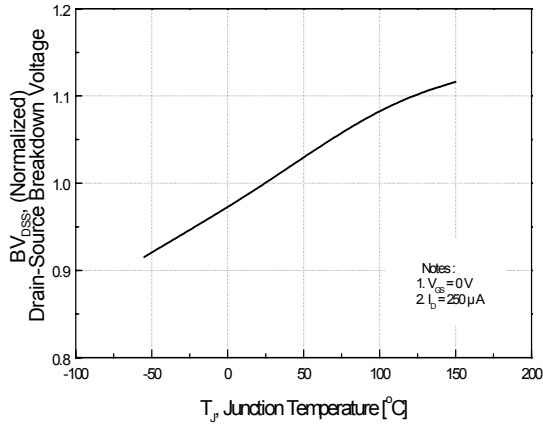


**Figure 6. Gate Charge Characteristics**

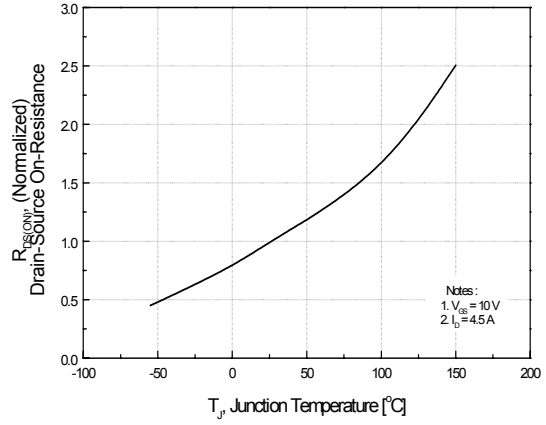


**Typical Performance Characteristics** (Continued)

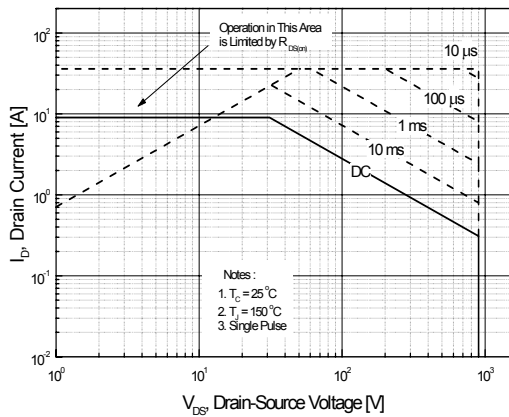
**Figure 7. Breakdown Voltage Variation vs. Temperature**



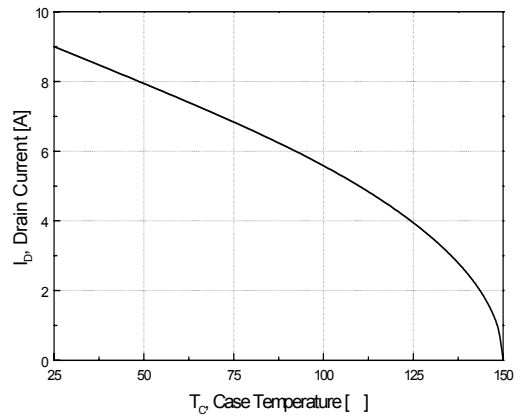
**Figure 8. On-Resistance Variation vs. Temperature**



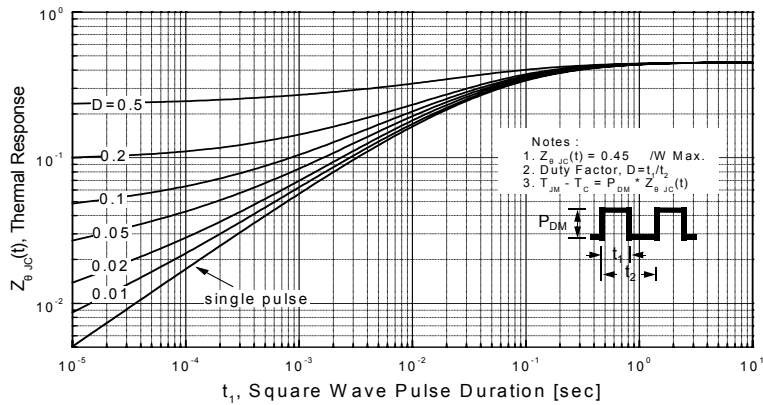
**Figure 9. Maximum Safe Operating Area**



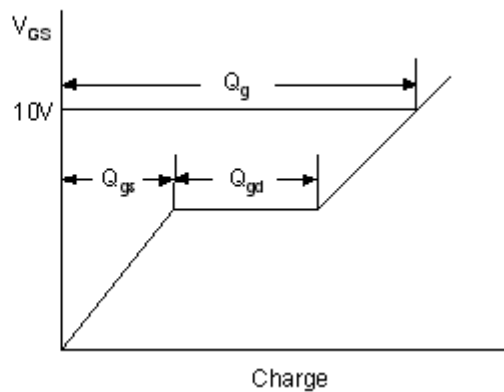
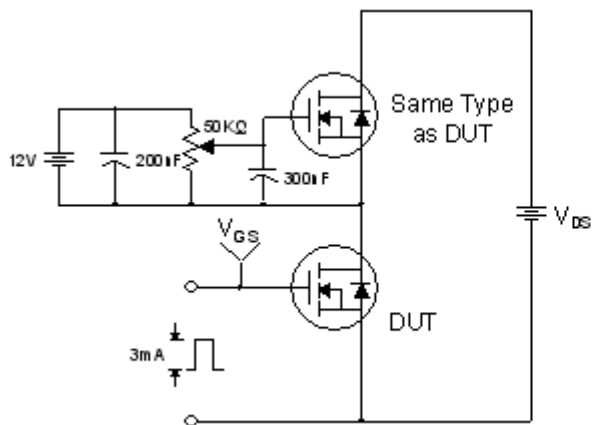
**Figure 10. Maximum Drain Current vs. Case Temperature**



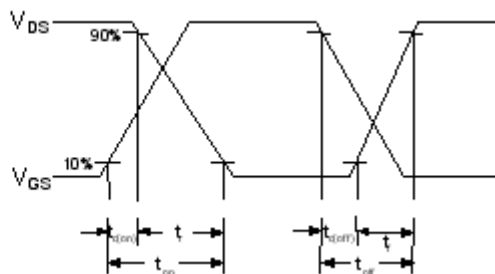
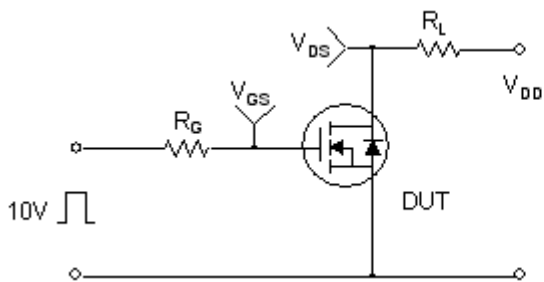
**Figure 11. Transient Thermal Response Curve**



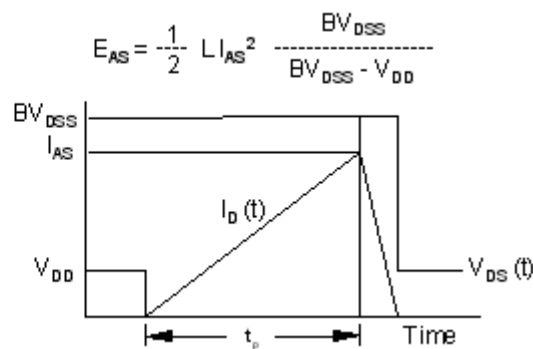
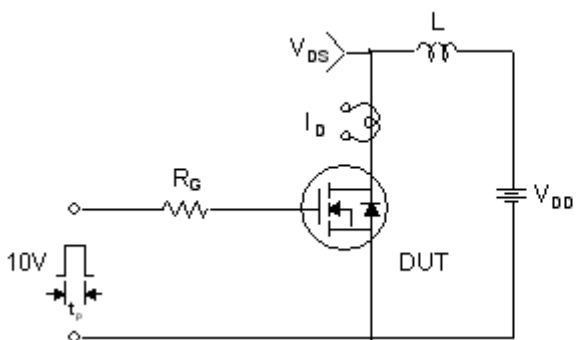
**Gate Charge Test Circuit & Waveform**



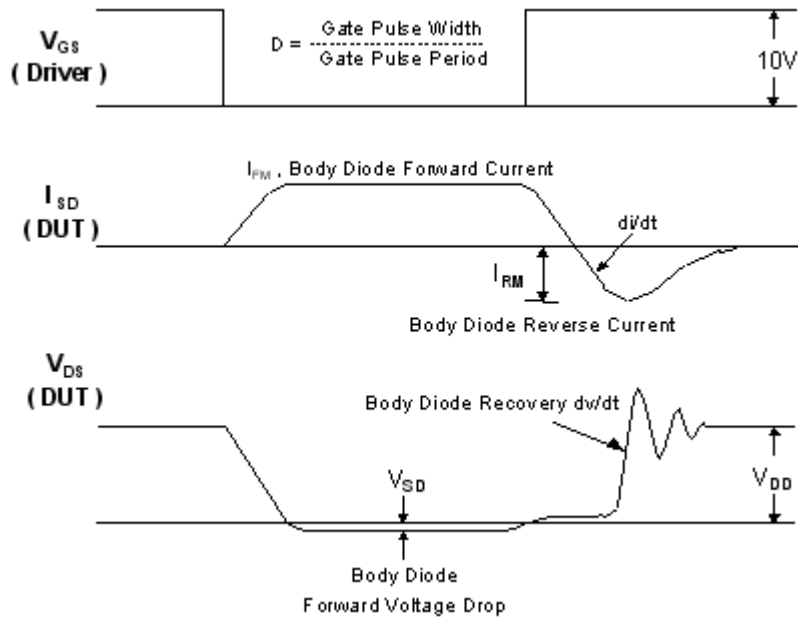
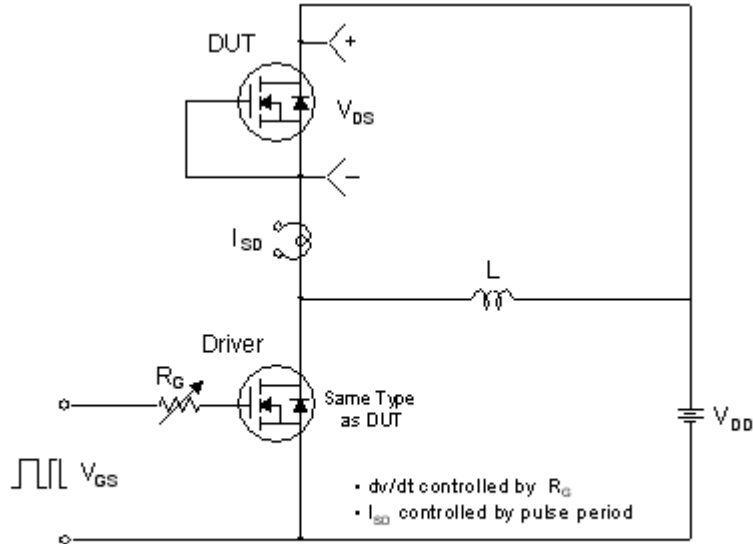
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**

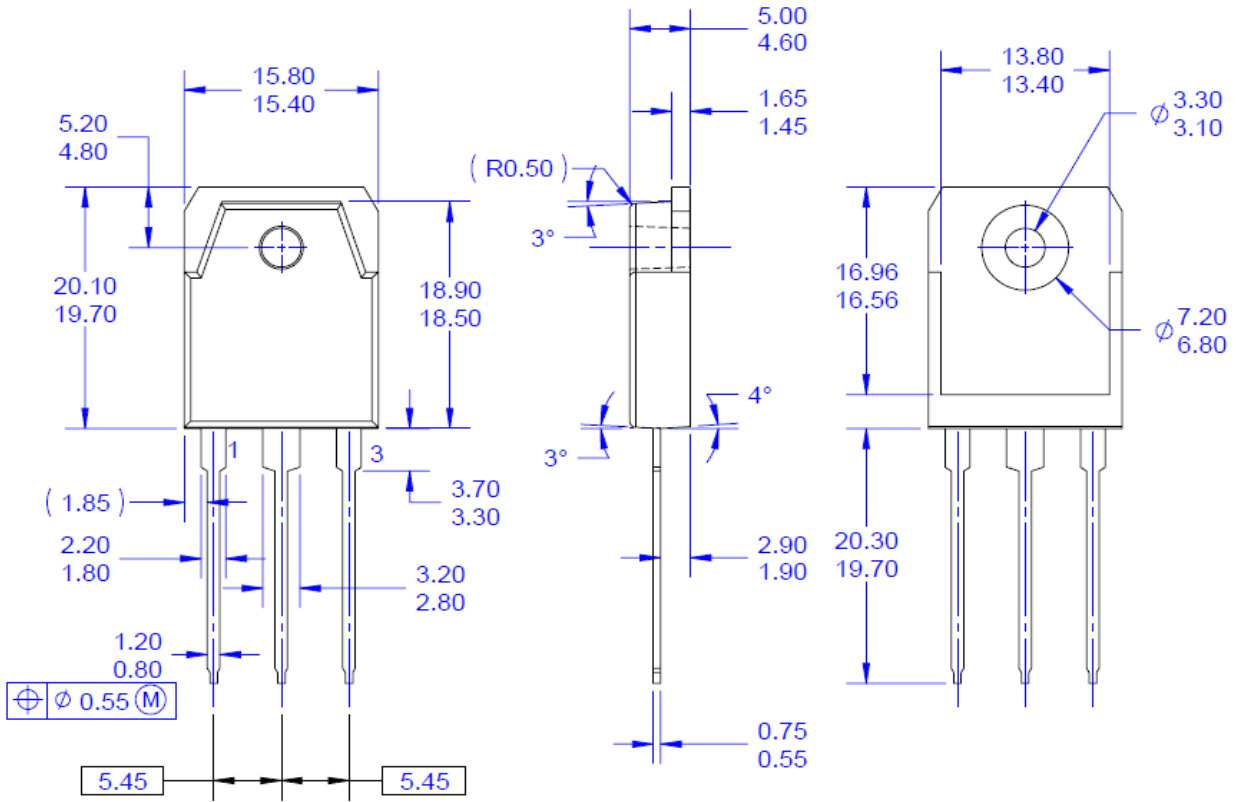


Peak Diode Recovery dv/dt Test Circuit & Waveforms



**Mechanical Dimensions**

**TO-3PN**



NOTES: UNLESS OTHERWISE SPECIFIED






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- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSION AND TOLERANCING PER ASME14.5
- D) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- E) THIS PACKAGE IS INTENDED ONLY FOR TO3PN.
- F) DRAWING FILE NAME: TO3P03AREV4.

Dimensions in Millimeters



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| BitSiC™   | Global Power Resource <sup>SM</sup>             | Programmable Active Droop™  | TinyBuck™   |
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Datasheet Identification	Product Status	Definition
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Rev. 164